## Notice of References Cited Application/Control No. 10/629,280 Applicant(s)/Patent Under Reexamination YUN ET AL. Examiner Thao P. Le Applicant(s)/Patent Under Reexamination YUN ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0187609	12-2002	Kim et al.	438/257
*	В	US-2003/0181053	09-2003	Tseng et al.	438/694
*	С	US-6,232,184	05-2001	Wang et al.	438/265
	D	US-2002/0106859	08-2002	Odake et al.	438/264
	Е	US-6,030,869	02-2000	Odake et al.	438/266
	F	US-6,027,971	02-2000	Cho et al.	438/257
	G	US-			
	Н	US-			
	-	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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